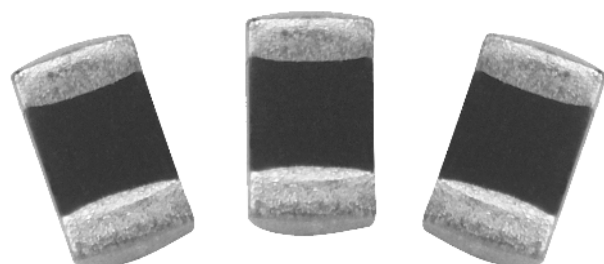


Surface Mount Multilayer Varistors



FEATURES

- Surface mount multilayer surge suppressor
- Inherent bidirectional clamping
- Low capacitance types available
- Excellent energy/volume ratio
- Suitable for wave or reflow soldering
- Compliance to IEC 1000-4-2

Size 0805 (2012M) multilayer chip varistor with AgPd terminations.

APPLICATIONS

- Data lines and I/O port protection
- Protection against EMI and ESD transients
- On-board protection of ICs and transistors
- Modem protection
- LCD protection

PACKAGING

Available in 8 mm paper tape on reel packaging and in bulk on request.

QUICK REFERENCE DATA		
PARAMETER	VALUE	UNIT
Maximum continuous voltage:		
DC	3.3 to 31	V
AC	2.5 to 25	V
Maximum clamping voltage at 1 A	12 to 65	V
Capacitance range	60 to 1300	pF
Maximum non-repetitive surge energy (10 × 1000 μs)	0.1	J
Maximum peak current (8 × 20 μs)	30	A
Response time (typical)	0.5	ns
Operating temperature range	-55 to 125	°C
Storage temperature range	-25 to 45	°C
Maximum continuous dissipation	5	mW

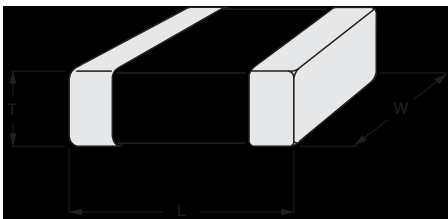
ELECTRICAL DATA AND ORDERING INFORMATION							
MAXIMUM OPERATING VOLTAGE		VOLTAGE ⁽²⁾ at 1 mA		MAXIMUM CLAMPING VOLTAGE at 1 A (V)	CAP. at 1 kHz (pF)	TOL. (%)	CATALOG NUMBERS 2322 574.....
RMS ⁽¹⁾ (V)	DC (V)	MIN. (V)	MAX. (V)				
2.5	3.3	4.1	6.0	12	1300	typ.	12583
4.0	5.5	6.4	9.6	21	470	typ.	10403
6.0	8.0	8.8	13.2	27	300	typ.	10603
8.0	11.0	12.7	17.2	33	200	typ.	10803
10.0	14.0	15.3	21.0	35	110	typ.	11003
14.0	18.0	19.8	25.7	40	100	typ.	11403
17.0	22.0	24.3	29.7	46	90	typ.	11703
20.0	26.0	29.7	38.6	56	70	typ.	12003
25.0	31.0	35.1	45.6	65	60	typ.	12503

Notes

1. The sinusoidal voltage is assumed as the normal operating condition. If a non-sinusoidal voltage is present, type selection should be based on multiplying the peak voltage by a factor of 0.707.
2. The voltage measured at 1 mA meets the requirements of "paragraph 4.3 of CECC specification 42000".

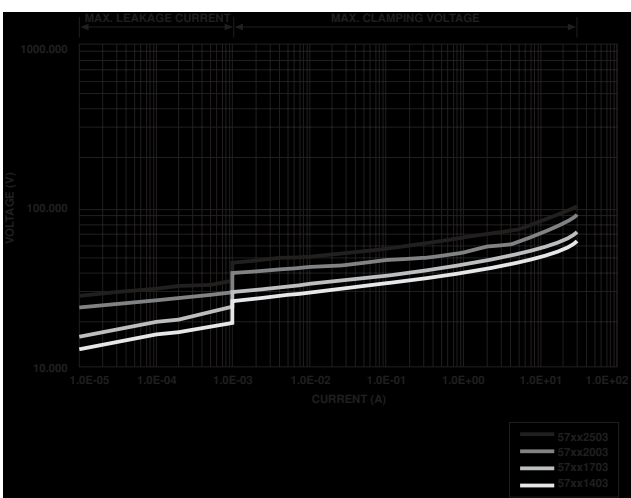
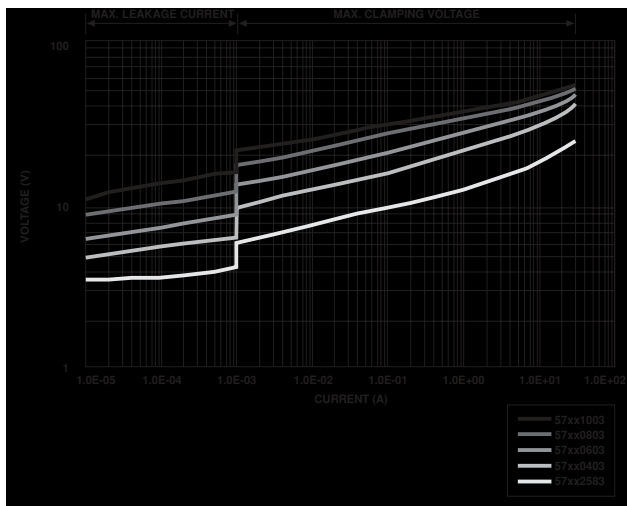


DIMENSIONS in millimeters



L	W	T
2.0 ±0.2	1.25 ±0.15	0.8 ± 0.15

V/I CHARACTERISTIC



TESTS AND REQUIREMENTS			
TEST / CONDITIONS OF TEST	D OR ND*	PROCEDURE	PERFORMANCE
Sub-group A1	ND		
Visual examination "IEC 4.3.1"			no visible damage
Sub-group A2	ND		
Voltage (CECC 4.3); Clamping voltage (CECC B.2.7)		at 1 mA	as specified
Sub-group A3	ND		
Dimensions (gauging) "IEC 4.3.3"			see 4.3.3
Sub-group B1	D		
Solderability: Test Td of "IEC 60068-2-20", solder bath method		235 °C ±5 °C for 5 ±0.5 s; at 1 mA	no visible damage; as in 9.2.1; as specified

* D = Destructive, N = Non-destructive